Nikon NSR-S204B

Lens Data Package

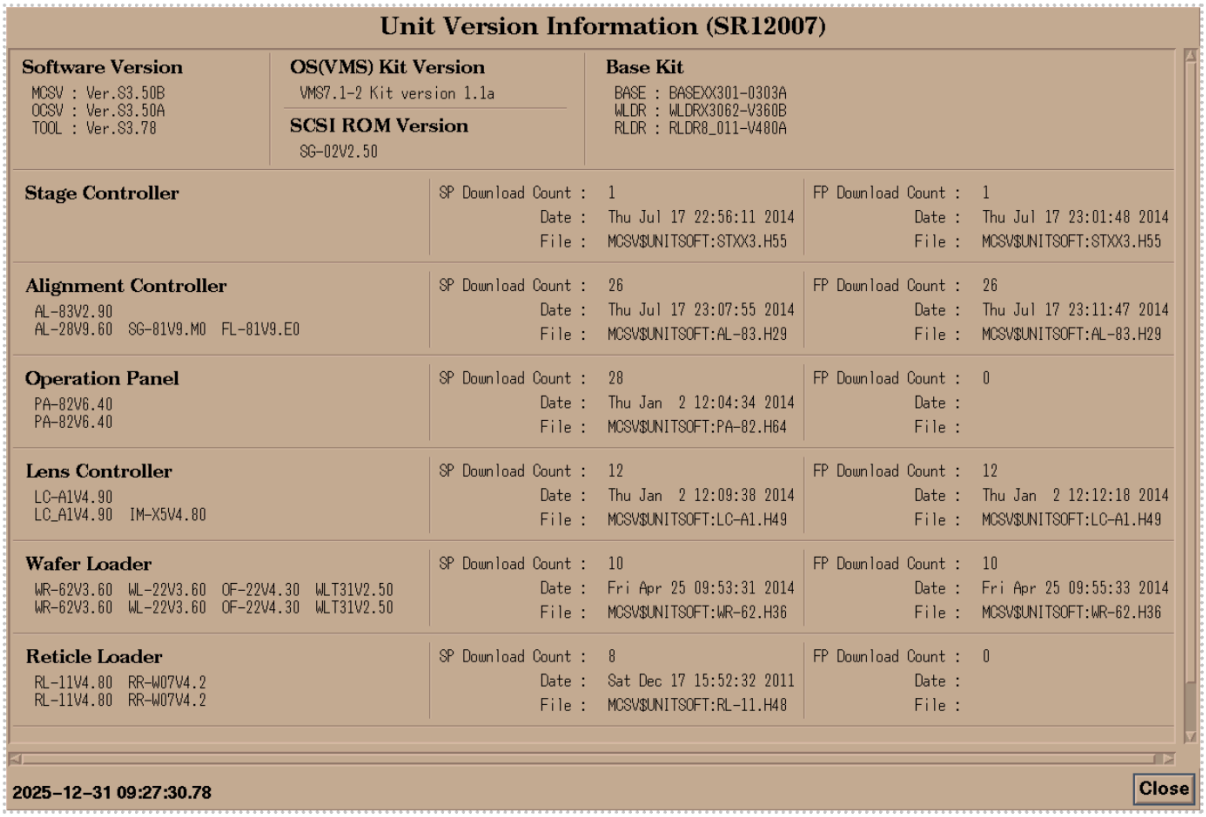
No	ITEM	SPEC	RESULT
1	Resolution (0.175um IsoLine) Conv NA/σ = 0.68/0.75	Customer Dependent based on CD Tolerance, SEM/15 Point in Field, V/H 0.175um Iso	Customer needs to calculate using Item2 DOF Data
2	DOF (0.175um IsoLine) Conv NA/σ = 0.68/0.75	Customer Dependent based on CD Tolerance, SEM/15 Point in Field, V/H 0.175um Iso	Customer needs to calculate
3	Linewidth Abnormality/COMA (0.175um L&S) Conv NA/σ = 0.68/0.44	[(L1 – L5) / (L1 + L5)] SEM/15 Point in Field, V/H 0.175um Iso	0.063 um
4	Total Focus Deviation Conv NA/σ = 0.68/0.75	(0.25μm L&S / 15Point V/H) Max-Min ≤ 0.20μm	0.222μm
5	Lens Astigmatisim Conv NA/σ = 0.68/0.75	(0.25μm L&S / 15Point V/H) |V-H| ≤ 0.20μm	0.119μm
6	Lens Dynamic Distortion Conv NA/σ = 0.68/0.75	X,Y = Within ±25nm	X = 12nm~57nm Y = -19nm~59nm
7	Lens Flare / IU Flare Conv NA/σ = 0.68/0.75	Customer Dependent	Lens Flare = 8.2% IU Flare = 1.54%
8	Wafer Flatness Accuracy	1) Flat Within ≥ Max-Min 3.0μm 2) L.F.S Within ≥ Max-Min 0.8μm	1. 1.41μm 2. 0.470μm
9	Exposure Power Conv NA/σ = 0.68/0.75	Within ≥ 700mW/cm2	528.71mW/cm2
10	Illumination Uniformity Conv NA/σ = 0.68/0.75	Within ±2%	1.5%
11	Orthogonality Accuracy	Within ± 0.48urad	±0.20urad
12	Stage Precision Accuracy 1) Stepping Accuracy 2) Backlash Accuracy	1) 3σ ≤ 25nm 2) 3σ ≤ 25nm	1. X: 14, 17, 18 Y: 14, 19, 15 2. X: 21, 20, 20 Y: 25, 25, 25
13	Wafer Pre-Alignment Repeatability	3σ≦15μm	X : 4.345 μm Y : 5.915 μm T : 6.280 μm

No	ITEM	SPEC	RESULT
14	Synchronization Accuracy 1) Mean 2) MSD	1) ≦10nm(-5nm ~ +5nm) 2) ≦ 25nm	1). X : 10nm, Y : 10nm 2). X : 24nm, Y : 14nm
15	AF Adjustment Result	PSD Max – Min ≤ 0.2μm	0.058μm
16	Integrator Accuracy	Target: 10, 20, 50, 100, 200mj/cm2 Ave ≤ 1.3%	Ave Max = 0.32%
17	Alignment Accuracy 1) FIA-EGA 2) LSA-EGA	FIA-EGA = |M| + 3σ ≤ 35nm LSA-EGA = |M| + 3σ ≤ 40nm	1) X = ±20nm Y = ±20nm 2) X= ±15nm Y = ±15nm

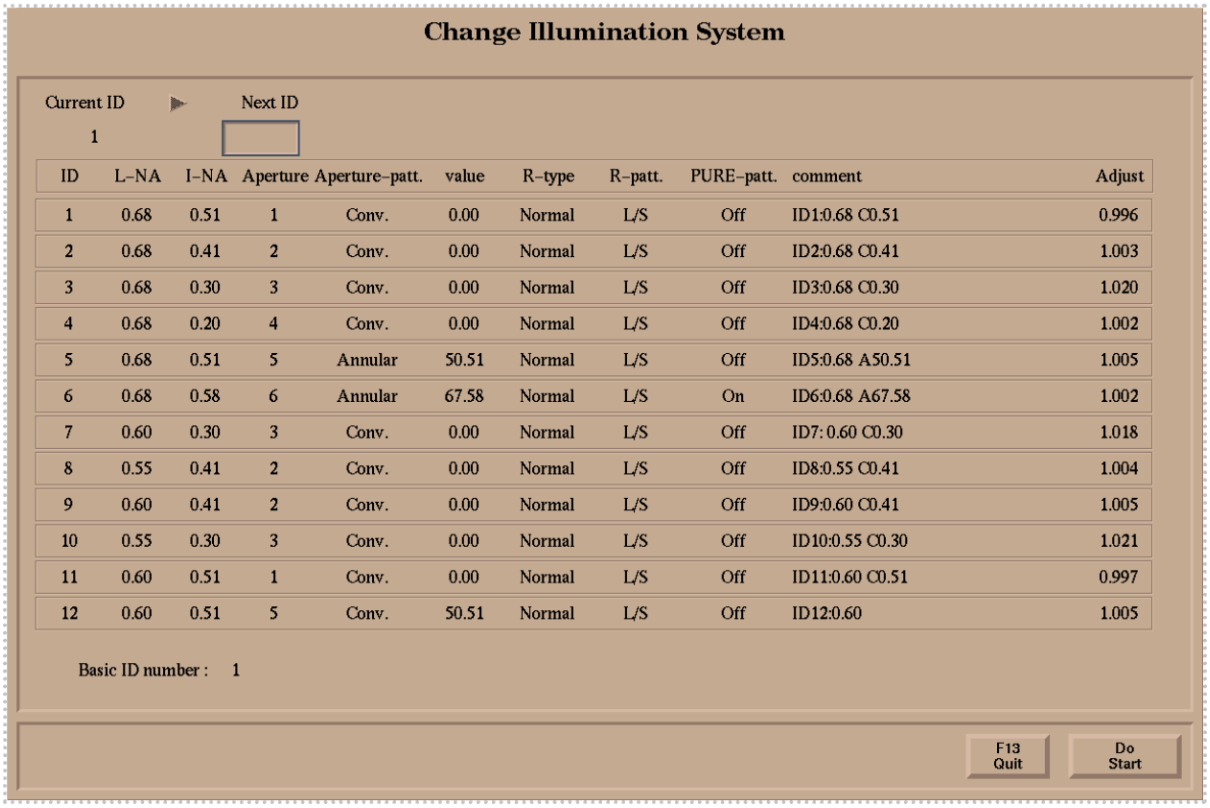
Software

MCSV Ver.S3.50B

OCSV Ver.S3.50A



Illumination System



Change Illumination System

Current ID ▶ Next ID

1

ID	L-NA	I-NA	Aperture	Aperture-patt.	value	R-type	R-patt.	PURE-patt.	comment	Adjust
1	0.68	0.51	1	Conv.	0.00	Normal	L/S	Off	ID1:0.68 C0.51	0.996
2	0.68	0.41	2	Conv.	0.00	Normal	L/S	Off	ID2:0.68 C0.41	1.003
3	0.68	0.30	3	Conv.	0.00	Normal	L/S	Off	ID3:0.68 C0.30	1.020
4	0.68	0.20	4	Conv.	0.00	Normal	L/S	Off	ID4:0.68 C0.20	1.002
5	0.68	0.51	5	Annular	50.51	Normal	L/S	Off	ID5:0.68 A50.51	1.005
6	0.68	0.58	6	Annular	67.58	Normal	L/S	On	ID6:0.68 A67.58	1.002
7	0.60	0.30	3	Conv.	0.00	Normal	L/S	Off	ID7: 0.60 C0.30	1.018
8	0.55	0.41	2	Conv.	0.00	Normal	L/S	Off	ID8:0.55 C0.41	1.004
9	0.60	0.41	2	Conv.	0.00	Normal	L/S	Off	ID9:0.60 C0.41	1.005
10	0.55	0.30	3	Conv.	0.00	Normal	L/S	Off	ID10:0.55 C0.30	1.021
11	0.60	0.51	1	Conv.	0.00	Normal	L/S	Off	ID11:0.60 C0.51	0.997
12	0.60	0.51	5	Conv.	50.51	Normal	L/S	Off	ID12:0.60	1.005

Basic ID number : 1

F13 Quit

Do Start

1. Lens Resolution (2019):

Conv NA/σ = 0.68/0.75

(0.175µm Isolated / 15Point V/H)

SPEC: Customer Dependent based on CD Tolerance

Result: Customer Needs to Calculate (Use Item2 DOF CD's at Best Focus)

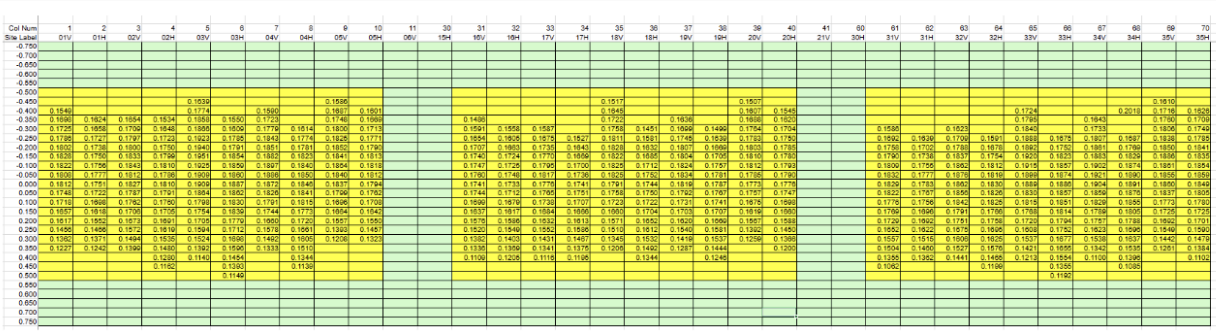
2. Depth of Focus (2019):

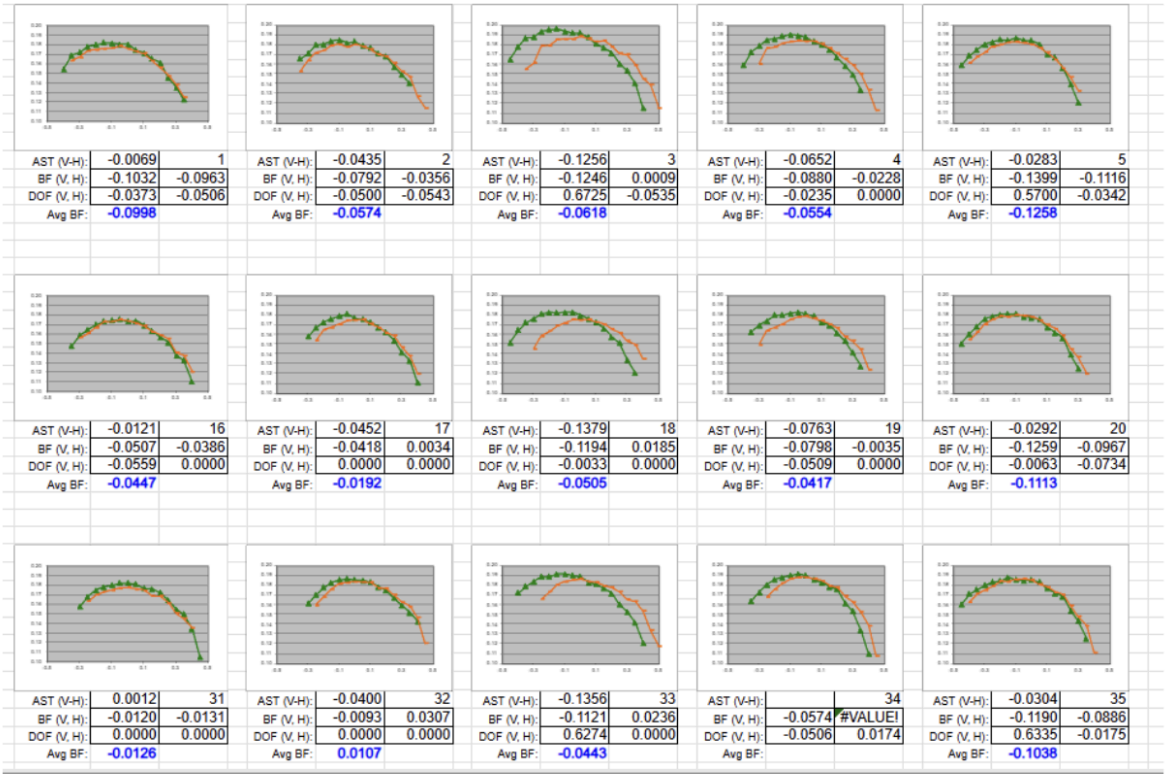
Conv NA/σ = 0.68/0.75

(0.175µm Isolated / 15Point V/H)

SPEC: Customer Dependent based on CD Tolerance

Result: Customer Needs to Calculate





AST (V-H):	-0.0069	1
BF (V, H):	-0.1032	-0.0963
DOF (V, H):	-0.0373	-0.0506
Avg BF:	-0.0998	

AST (V-H):	-0.0435	2
BF (V, H):	-0.0792	-0.0356
DOF (V, H):	-0.0500	-0.0543
Avg BF:	-0.0574	

AST (V-H):	-0.1256	3
BF (V, H):	-0.1246	0.0009
DOF (V, H):	0.6725	-0.0535
Avg BF:	-0.0618	

AST (V-H):	-0.0652	4
BF (V, H):	-0.0880	-0.0228
DOF (V, H):	-0.0235	0.0000
Avg BF:	-0.0554	

AST (V-H):	-0.0283	5
BF (V, H):	-0.1399	-0.1116
DOF (V, H):	0.5700	-0.0342
Avg BF:	-0.1258	

AST (V-H):	-0.0121	16
BF (V, H):	-0.0507	-0.0386
DOF (V, H):	-0.0559	0.0000
Avg BF:	-0.0447	

AST (V-H):	-0.0452	17
BF (V, H):	-0.0418	0.0034
DOF (V, H):	0.0000	0.0000
Avg BF:	-0.0192	

AST (V-H):	-0.1379	18
BF (V, H):	-0.1194	0.0185
DOF (V, H):	-0.0033	0.0000
Avg BF:	-0.0505	

AST (V-H):	-0.0763	19
BF (V, H):	-0.0798	-0.0035
DOF (V, H):	-0.0509	0.0000
Avg BF:	-0.0417	

AST (V-H):	-0.0292	20
BF (V, H):	-0.1259	-0.0967
DOF (V, H):	-0.0063	-0.0734
Avg BF:	-0.1113	

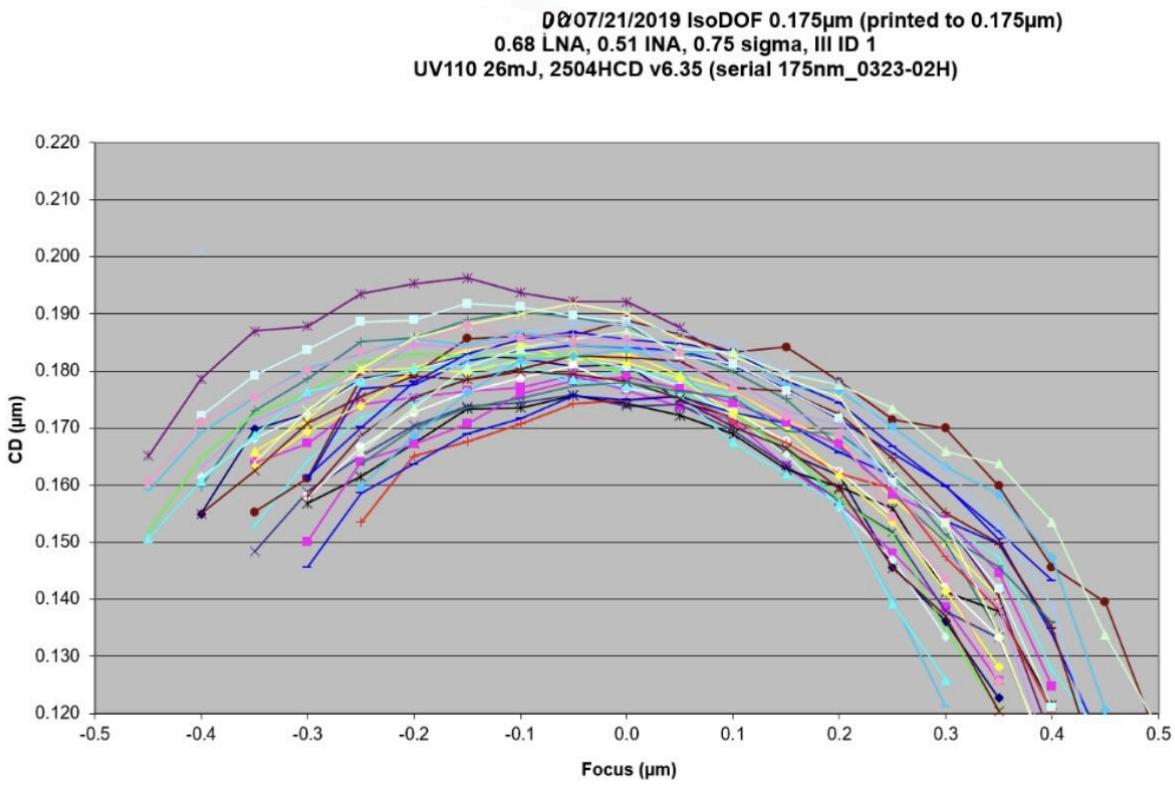
AST (V-H):	0.0012	31
BF (V, H):	-0.0120	-0.0131
DOF (V, H):	0.0000	0.0000
Avg BF:	-0.0126	

AST (V-H):	-0.0400	32
BF (V, H):	-0.0093	0.0307
DOF (V, H):	0.0000	0.0000
Avg BF:	0.0107	

AST (V-H):	-0.1356	33
BF (V, H):	-0.1121	0.0236
DOF (V, H):	0.6274	0.0000
Avg BF:	-0.0443	

AST (V-H):		34
BF (V, H):	-0.0574	#VALUE!
DOF (V, H):	-0.0506	0.0174
Avg BF:		

AST (V-H):	-0.0304	35
BF (V, H):	-0.1190	-0.0886
DOF (V, H):	0.6335	-0.0175
Avg BF:	-0.1038	



3. Linewidth Abnormality / COMA (2019):

Conv NA/σ = 0.68/0.44

(0.175µm L/S / 15Point V/H)

SPEC: 0.055µm (Customer Dependent)

Result: 0.063µm

Center Dose: 25mJ	Tool Name: U92V	Spec:(um)	<=	0.055	Best Dose: 24	Track Recipe: N01_LENSOP-LNK
Dose Step: 1mJ	Exp Date: 7/10/2019	Result:(um)		0.063 Fail	Best Focus: -0.05	Nikon Recipe: 0IBM_CDV3.C21R5
Center Focus: 0um	SEM Name: S55V	Max Delta (um):		0.020	18V L3 (@ BD/BF): 0.182	SEM Recipe: 0_032302H_175_COMA
Focus Step: 0.05um	Meas Date: 7/20/2019	Max	0.063		18V L1 (@ BD/BF): 0.206	Reticle: HCD #0323-02H
Exposed By: Mike F.	Meas By: Mike M.	Min	-0.059		18V L5 (@ BD/BF): 0.198	Comment: Annual Lens Health
	ID#: 3					

Reticle Error Removed

	11				12				13				14				15			
	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H
	172	165	160	174	199	189	186	209	216	209	202	223	201	193	189	207	174	169	171	176
	0.021		-0.044		0.025		-0.059		0.017		-0.049		0.020		-0.046		0.013		-0.014	
	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45
	178	164	171	165	206	190	194	191	217	206	214	220	195	190	199	208	172	164	168	178
	0.042		0.017		0.039		0.006		0.028		-0.013		0.013		-0.022		0.022		-0.030	
	16				17				18				19				20			
	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H
	170	164	162	168	197	192	188	191	210	202	203	194	203	189	196	190	167	159	163	162
	0.017		-0.020		0.012		-0.007		0.018		0.022		0.036		0.016		0.025		0.002	
	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45
	172	159	168	163	195	189	199	190	197	205	207	200	192	197	194	194	162	156	157	166
	0.039		0.013		0.017		0.022		-0.020		0.017		-0.011		0.001		0.017		-0.028	
	21				22				23				24				25			
	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H	L1 V	L5 V	L1 H	L5 H
	167	161	161	164	180	178	190	169	197	189	204	180	187	174	196	176	165	150	160	162
	0.021		-0.011		0.005		0.058		0.021		0.063		0.035		0.055		0.048		-0.006	
	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45	L1 135	L5 135	L1 45	L5 45
	169	157	163	166	174	182	189	180	186	201	203	189	184	185	187	176	166	150	156	160
	0.037		-0.008		-0.022		0.023		-0.041		0.037		-0.003		0.030		0.050		-0.011	

Summary Results

	90	0	135	45
11	0.021	-0.044	0.042	0.017
12	0.025	-0.059	0.039	0.006
13	0.017	-0.049	0.028	-0.013
14	0.020	-0.046	0.013	-0.022
15	0.013	-0.014	0.022	-0.030
16	0.017	-0.020	0.039	0.013
17	0.012	-0.007	0.017	0.022
18	0.018	0.022	-0.020	0.017
19	0.036	0.016	-0.011	0.001
20	0.025	0.002	0.017	-0.028
21	0.021	-0.011	0.037	-0.008
22	0.005	0.058	-0.022	0.023
23	0.021	0.063	-0.041	0.037
24	0.035	0.055	-0.003	0.030
25	0.048	-0.006	0.050	-0.011

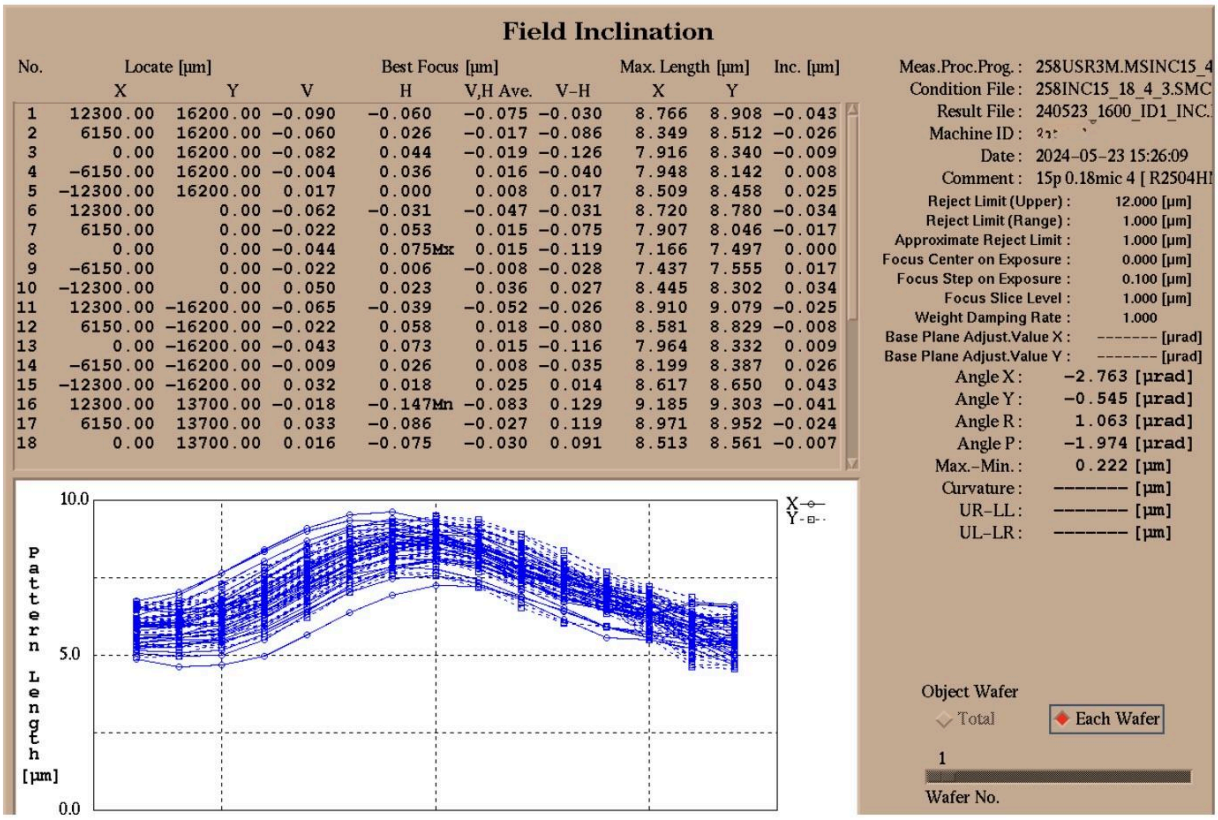
4. Total Focus Deviation (2024):

Conv NA/σ = 0.68/0.75

(0.25µm L&S / 15Point V/H)

SPEC: Max-Min≤0.20µm

Result: Max – Min = 0.222µm



Field Inclination

No.	Locate [µm] X	Y	V	Best Focus [µm] H	V,H Ave.	V–H	Max. Length [µm] X	Y	Inc. [µm]
1	12300.00	16200.00	-0.090	-0.060	-0.075	-0.030	8.766	8.908	-0.043
2	6150.00	16200.00	-0.060	0.026	-0.017	-0.086	8.349	8.512	-0.026
3	0.00	16200.00	-0.082	0.044	-0.019	-0.126	7.916	8.340	-0.009
4	-6150.00	16200.00	-0.004	0.036	0.016	-0.040	7.948	8.142	0.008
5	-12300.00	16200.00	0.017	0.000	0.008	0.017	8.509	8.458	0.025
6	12300.00	0.00	-0.062	-0.031	-0.047	-0.031	8.720	8.780	-0.034
7	6150.00	0.00	-0.022	0.053	0.015	-0.075	7.907	8.046	-0.017
8	0.00	0.00	-0.044	0.075Max	0.015	-0.119	7.166	7.497	0.000
9	-6150.00	0.00	-0.022	0.006	-0.008	-0.028	7.437	7.555	0.017
10	-12300.00	0.00	0.050	0.023	0.036	0.027	8.445	8.302	0.034
11	12300.00	-16200.00	-0.065	-0.039	-0.052	-0.026	8.910	9.079	-0.025
12	6150.00	-16200.00	-0.022	0.058	0.018	-0.080	8.581	8.829	-0.008
13	0.00	-16200.00	-0.043	0.073	0.015	-0.116	7.964	8.332	0.009
14	-6150.00	-16200.00	-0.009	0.026	0.008	-0.035	8.199	8.387	0.026
15	-12300.00	-16200.00	0.032	0.018	0.025	0.014	8.617	8.650	0.043
16	12300.00	13700.00	-0.018	-0.147Min	-0.083	0.129	9.185	9.303	-0.041
17	6150.00	13700.00	0.033	-0.086	-0.027	0.119	8.971	8.952	-0.024
18	0.00	13700.00	0.016	-0.075	-0.030	0.091	8.513	8.561	-0.007

Meas.Proc.Prog. : 258USR3M.MSINC15_4
Condition File : 258INC15_18_4_3.SMC
Result File : 240523_1600_ID1_INC.
Machine ID : [illegible]
Date : 2024-05-23 15:26:09
Comment : 15p 0.18mic 4 [R2504H
Reject Limit (Upper) : 12.000 [µm]
Reject Limit (Range) : 1.000 [µm]
Approximate Reject Limit : 1.000 [µm]
Focus Center on Exposure : 0.000 [µm]
Focus Step on Exposure : 0.100 [µm]
Focus Slice Level : 1.000 [µm]
Weight Damping Rate : 1.000
Base Plane Adjust.Value X : ------- [µrad]
Base Plane Adjust.Value Y : ------- [µrad]
Angle X : -2.763 [µrad]
Angle Y : -0.545 [µrad]
Angle R : 1.063 [µrad]
Angle P : -1.974 [µrad]
Max.–Min. : 0.222 [µm]
Curvature : ------- [µm]
UR–LL : ------- [µm]
UL–LR : ------- [µm]

Object Wafer
Total
Each Wafer
1
Wafer No.

5. Lens Astigmatism (2024):

Conv NA/σ = 0.68/0.75

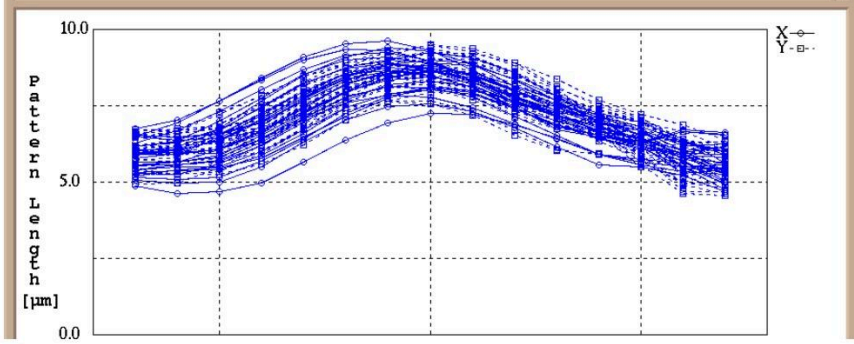
(0.25µm L&S / 15Point V/H)

SPEC: |V-H| ≤0.20µm

Result: |V-H| = 0.119µm

Field Inclination

No.	Locate [µm]			Best Focus [µm]			Max. Length [µm]		Inc. [µm]
	X	Y	V	H	V,H Ave.	V–H	X	Y	
1	12300.00	16200.00	-0.090	-0.060	-0.075	-0.030	8.766	8.908	-0.043
2	6150.00	16200.00	-0.060	0.026	-0.017	-0.086	8.349	8.512	-0.026
3	0.00	16200.00	-0.082	0.044	-0.019	-0.126	7.916	8.340	-0.009
4	-6150.00	16200.00	-0.004	0.036	0.016	-0.040	7.948	8.142	0.008
5	-12300.00	16200.00	0.017	0.000	0.008	0.017	8.509	8.458	0.025
6	12300.00	0.00	-0.062	-0.031	-0.047	-0.031	8.720	8.780	-0.034
7	6150.00	0.00	-0.022	0.053	0.015	-0.075	7.907	8.046	-0.017
8	0.00	0.00	-0.044	0.075Mx	0.015	-0.119	7.166	7.497	0.000
9	-6150.00	0.00	-0.022	0.006	-0.008	-0.028	7.437	7.555	0.017
10	-12300.00	0.00	0.050	0.023	0.036	0.027	8.445	8.302	0.034
11	12300.00	-16200.00	-0.065	-0.039	-0.052	-0.026	8.910	9.079	-0.025
12	6150.00	-16200.00	-0.022	0.058	0.018	-0.080	8.581	8.829	-0.008
13	0.00	-16200.00	-0.043	0.073	0.015	-0.116	7.964	8.332	0.009
14	-6150.00	-16200.00	-0.009	0.026	0.008	-0.035	8.199	8.387	0.026
15	-12300.00	-16200.00	0.032	0.018	0.025	0.014	8.617	8.650	0.043
16	12300.00	13700.00	-0.018	-0.147Mn	-0.083	0.129	9.185	9.303	-0.041
17	6150.00	13700.00	0.033	-0.086	-0.027	0.119	8.971	8.952	-0.024
18	0.00	13700.00	0.016	-0.075	-0.030	0.091	8.513	8.561	-0.007



Meas.Proc.Prog. :	258USR3M.MSINC15_4
Condition File :	258INC15_18_4_3.SMC
Result File :	240523 1600_ID1_INC.
Machine ID :	
Date :	2024-05-23 15:26:09
Comment :	15p 0.18mic 4 [R2504H
Reject Limit (Upper) :	12.000 [µm]
Reject Limit (Range) :	1.000 [µm]
Approximate Reject Limit :	1.000 [µm]
Focus Center on Exposure :	0.000 [µm]
Focus Step on Exposure :	0.100 [µm]
Focus Slice Level :	1.000 [µm]
Weight Damping Rate :	1.000
Base Plane Adjust.Value X :	------- [µrad]
Base Plane Adjust.Value Y :	------- [µrad]
Angle X :	-2.763 [µrad]
Angle Y :	-0.545 [µrad]
Angle R :	1.063 [µrad]
Angle P :	-1.974 [µrad]
Max.-Min. :	0.222 [µm]
Curvature :	------- [µm]
UR-LL :	------- [µm]
UL-LR :	------- [µm]

Object Wafer

◇ Total ◆ Each Wafer

1

Wafer No.

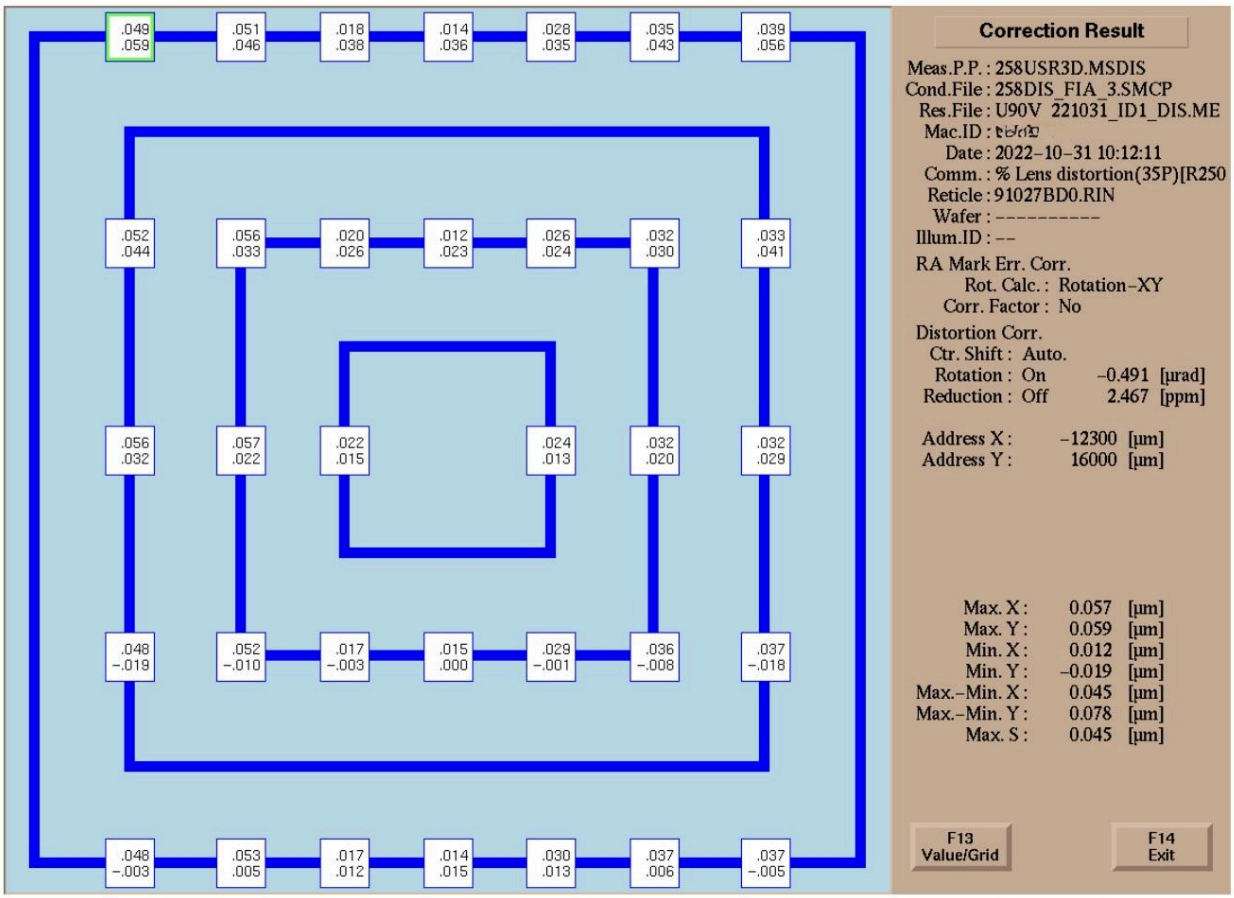
6. Lens Dynamic Distortion (2022):

Conv NA/σ = 0.68/0.75

SPEC: X,Y = Within ±25nm

Result: X = 12nm~57nm

Y = -19nm~59nm



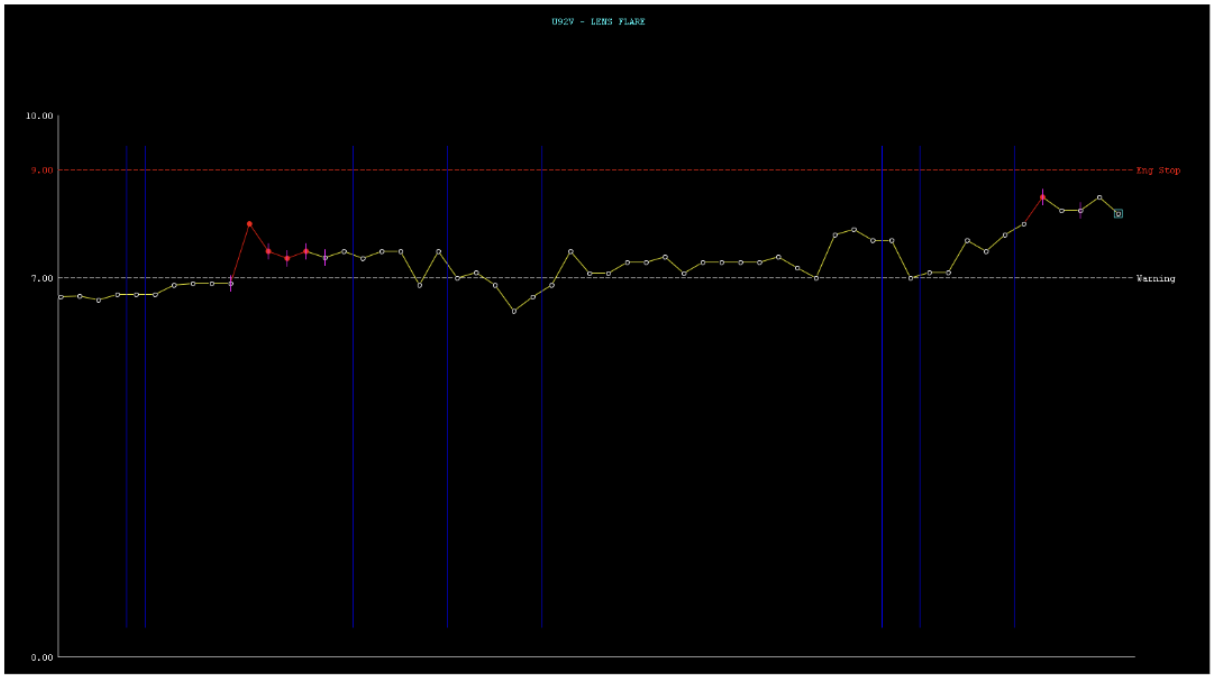
7. Lens Flare/IU Flare (2024):

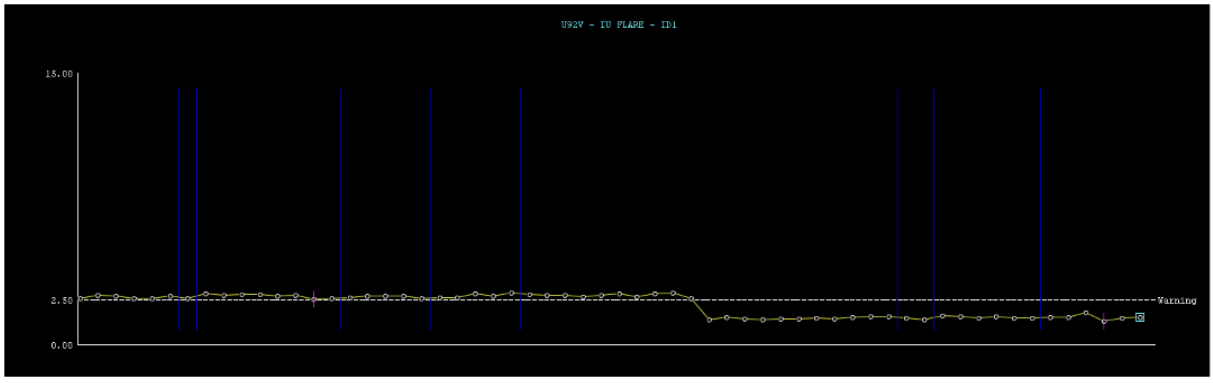
Conv NA/σ = 0.68/0.75

SPEC: TBD based on Product Requirements

Results: Lens Flare = 8.2% IU Flare = 1.54%

From Nikon Lens Flare Test with RPF installed

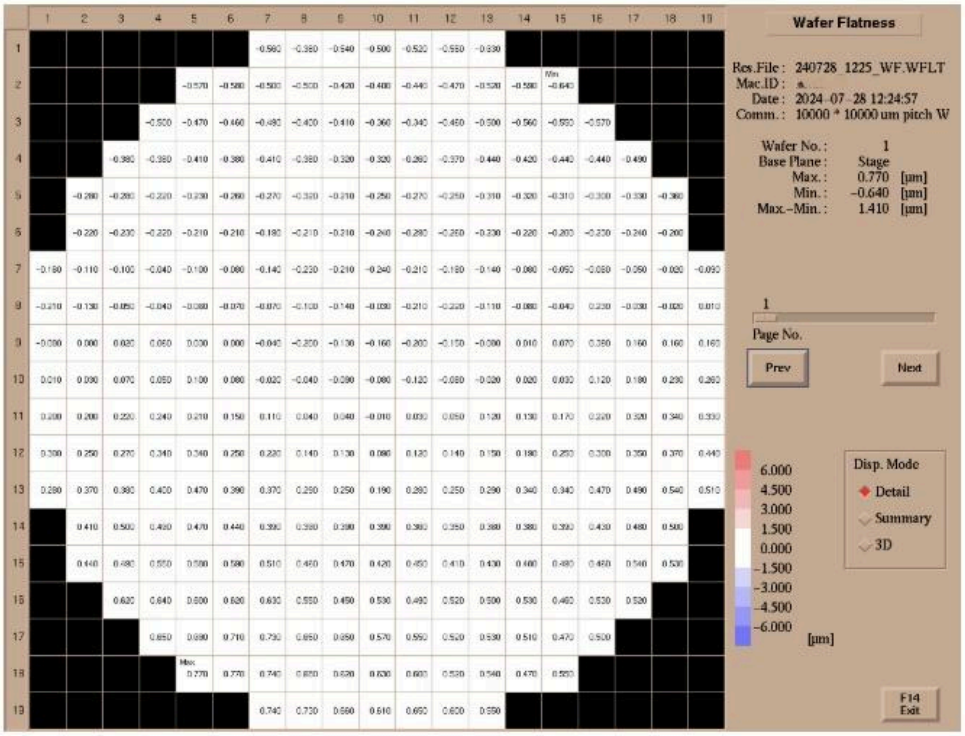




8. Wafer Flatness Accuracy (2024):

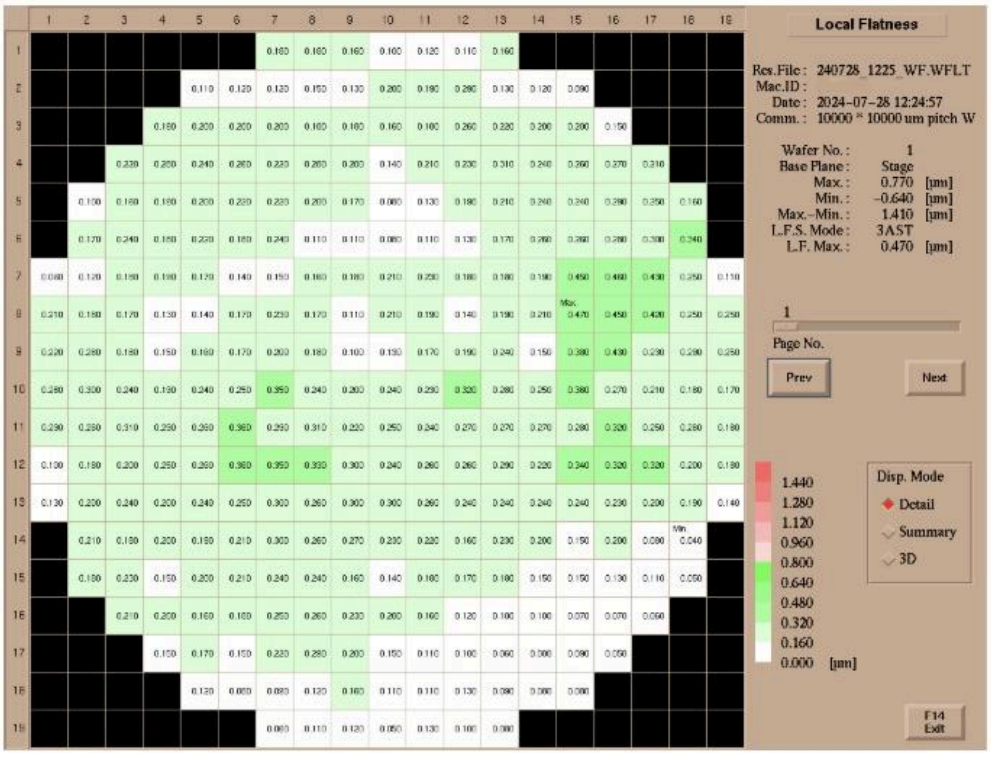
SPEC: 1) Flat Within ≥ Max-Min 3.0μm

Result: Max-Min = 1.41μm



SPEC: 2) L.F.S Within ≥ Max-Min 0.8μm

Result: Max-Min = 0.470μm



9/10 Exposure Power / Uniformity (2024):

Conv NA/σ = 0.68/0.75

SPEC: Power = Within ≥ 700mW/cm2

Spec: Uniformity Within ±2%

Result: 1) Illumination Power = 528.71mW/cm2

2) Uniformity = 1.50%

Note: 22% RPF installed

	1	2	3	4	5	6	7	8	9	10	11
1	Min. 945	978	987	983	978	975	971	968	965	954	954
2	946	978	981	975	971	968	963	960	959	949	954
3	948	977	977	970	967	965	962	956	956	949	974
4	950	976	974	970	969	968	964	956	953	947	982
5	952	977	974	967	969	972	967	954	954	949	983
6	953	978	974	968	969	973	966	956	956	948	984
7	953	981	975	969	971	970	967	959	957	952	986
8	955	983	979	974	973	974	969	963	962	953	989
9	956	987	988	979	975	974	970	966	966	957	990
10	957	989	994	987	982	979	977	975	973	962	991

Illumination Uniformity

Res.File : 240314 LAMP_CE.LA
Mac.ID :
Date : 2024-03-14 11:39:10
Comm. : LPC=, IUC=2.5, RPF2=
Illumination ID : 1

Center
Maximum : 1000.00
Minimum : 944.65

Center (Integral)
Maximum : 1012.57
Minimum : 982.60
Uniformity : 1.50 [%]

Illumination
Power : 528.71 [mW/cm²]

Intra-field Repeat Count : 1
Intra-field Repeat No. 1

978
976
974
972
970
968
966
964
962

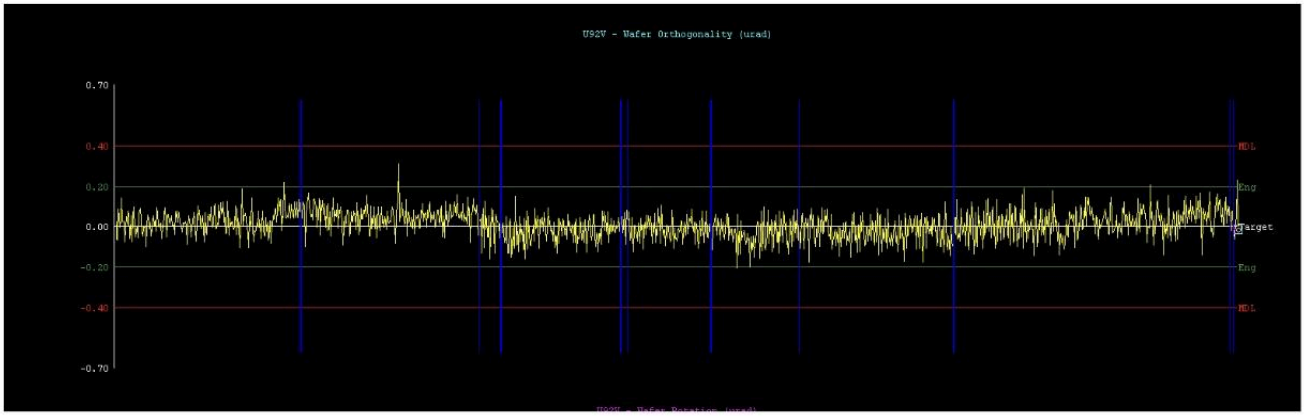
Disp. Mode
Detail
Summary
3D

11. Orthogonality:

SPEC: Within ±0.48uran

Result: 0.20urad

Data is from [redacted] Overlay Tool Checks 2020-2024



12. Stage Precision Accuracy (2014):

SPEC: Step X,Y 3σ ≤ 25nm

Backlash X,Y 3σ ≤ 25nm

Result:

1) Stepping Accuracy

SX1(3σ) : 14nm SY1(3σ) : 14nm

SX2(3σ) : 17nm SY2(3σ) : 19nm

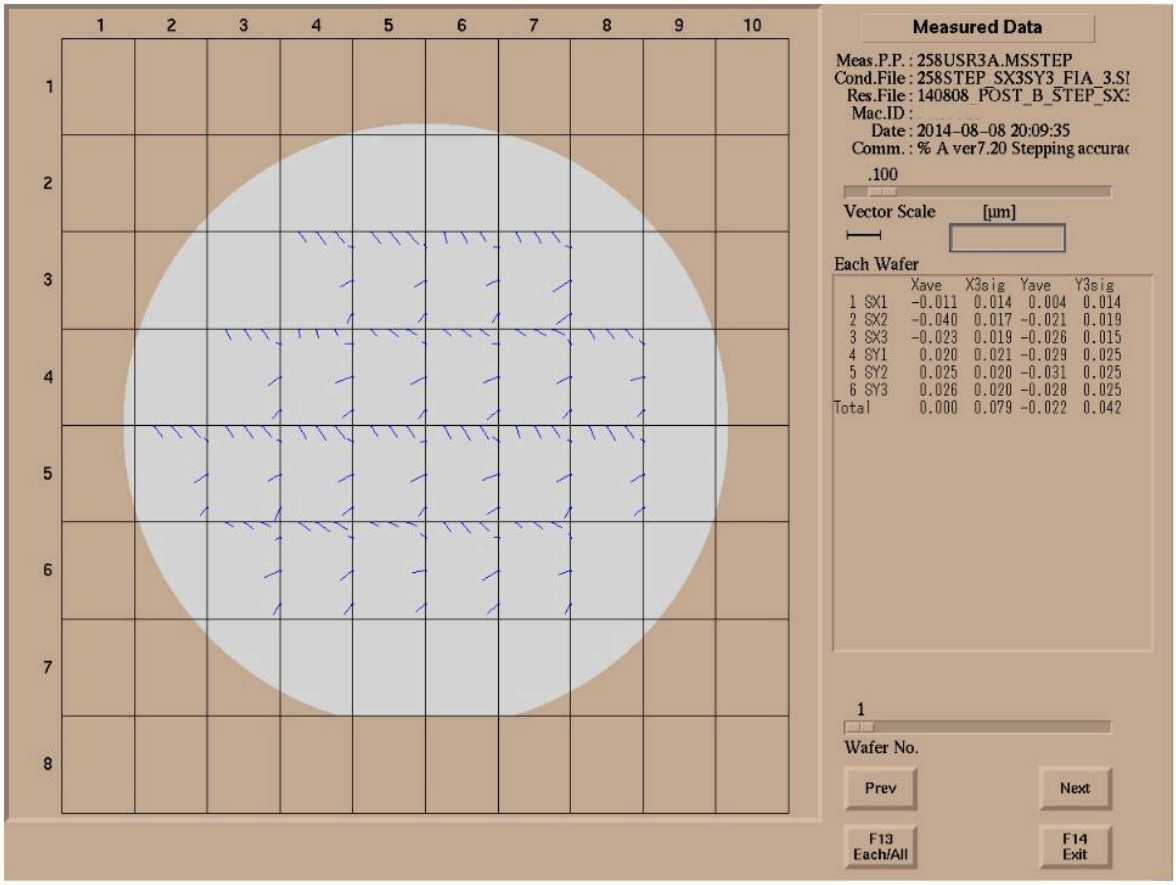
SX3(3σ) : 18nm SY3(3σ) : 15nm

2) Backlash Accuracy

SX1(3σ) : 21nm SY1(3σ) : 25nm

SX2(3σ) : 20nm SY2(3σ) : 25nm

SX3(3σ) : 20nm SY3(3σ) : 25nm



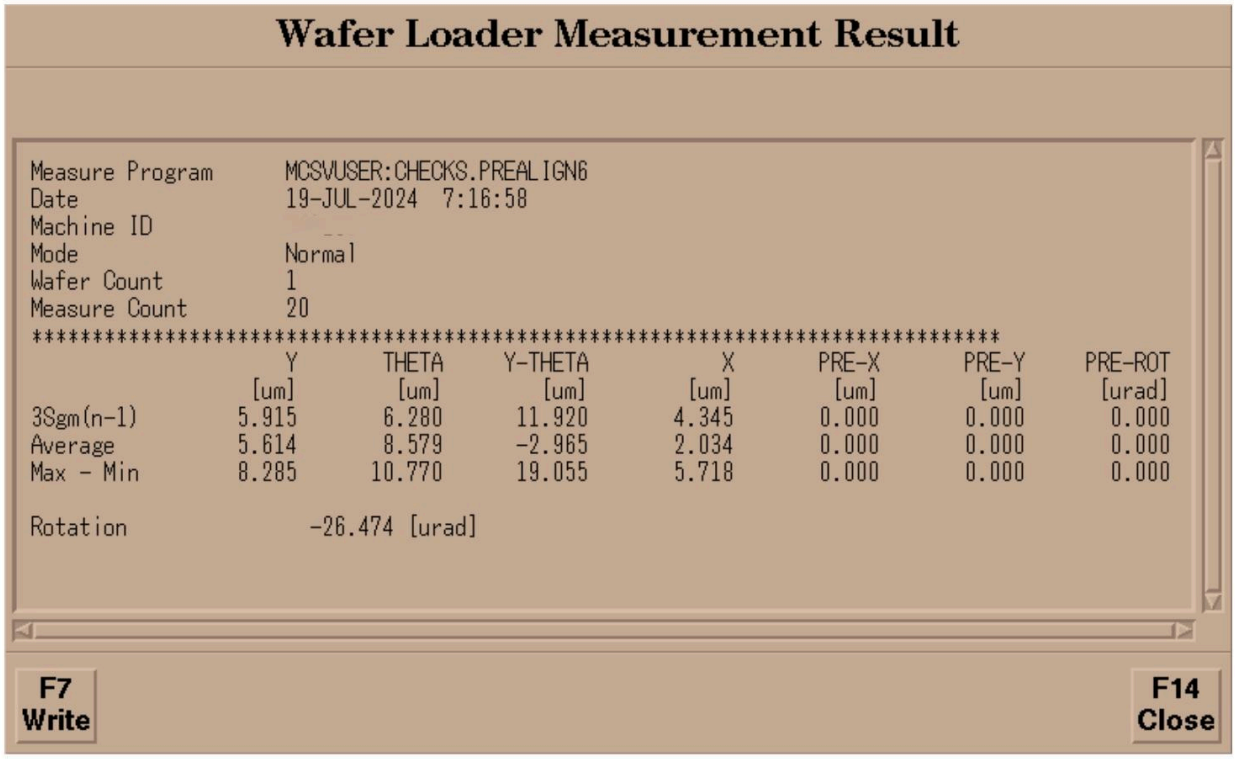
13. Wafer Pre-Alignment Repeatability (2024):

SPEC: 3σ ≤ 15µm

Result: X(3σ) = 4.345µm

Y(3σ) = 5.915µm

T(3σ) = 6.280µm



Wafer Loader Measurement Result

Measure Program MCSVUSER:CHECKS.PREALIGN6
Date 19-JUL-2024 7:16:58
Machine ID
Mode Normal
Wafer Count 1
Measure Count 20

	Y [um]	THETA [um]	Y-THETA [um]	X [um]	PRE-X [um]	PRE-Y [um]	PRE-ROT [urad]
3Sgm(n-1)	5.915	6.280	11.920	4.345	0.000	0.000	0.000
Average	5.614	8.579	-2.965	2.034	0.000	0.000	0.000
Max - Min	8.285	10.770	19.055	5.718	0.000	0.000	0.000

Rotation -26.474 [urad]

F7 Write

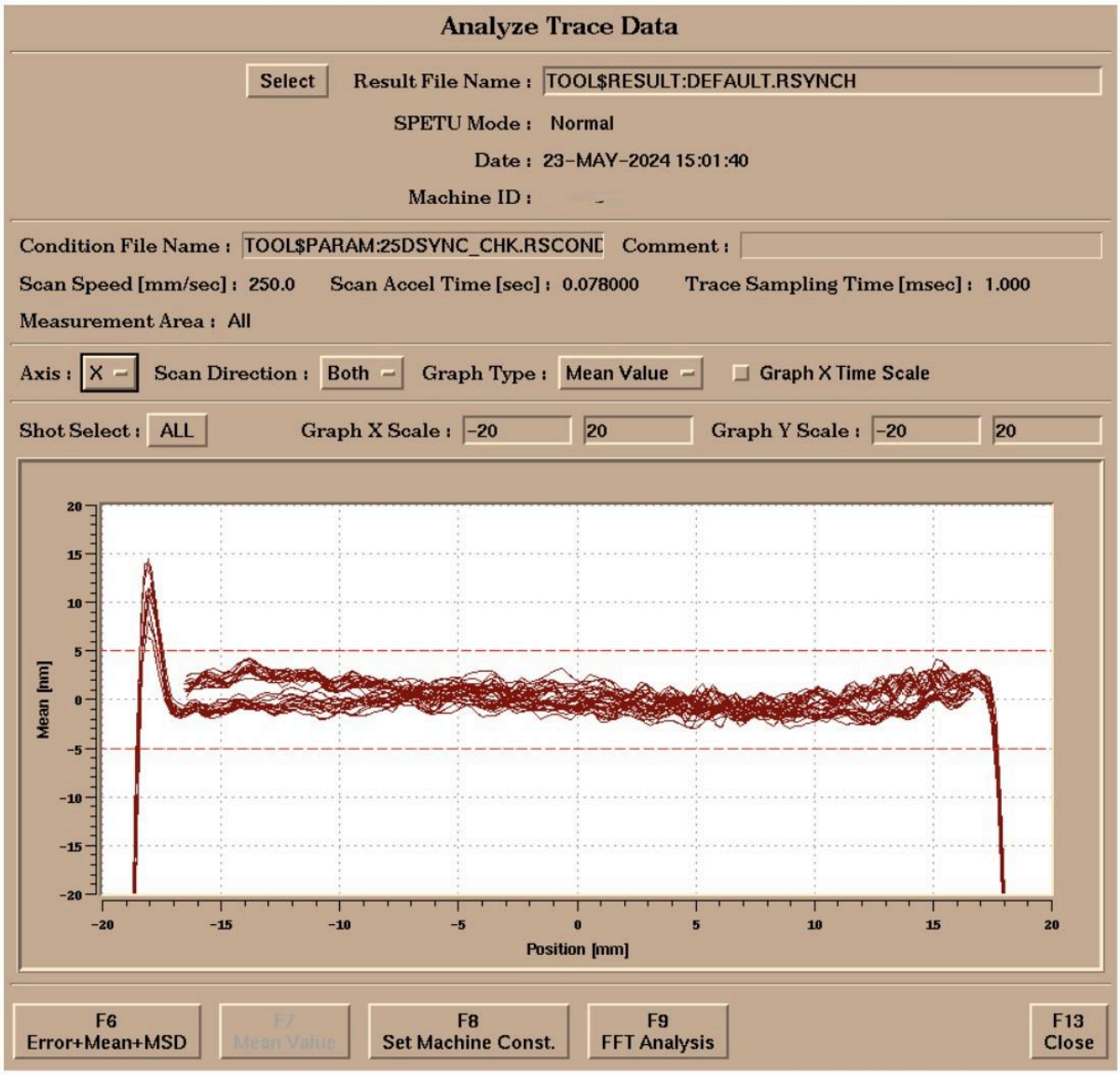
F14 Close

14. Synchronization Accuracy (2024):

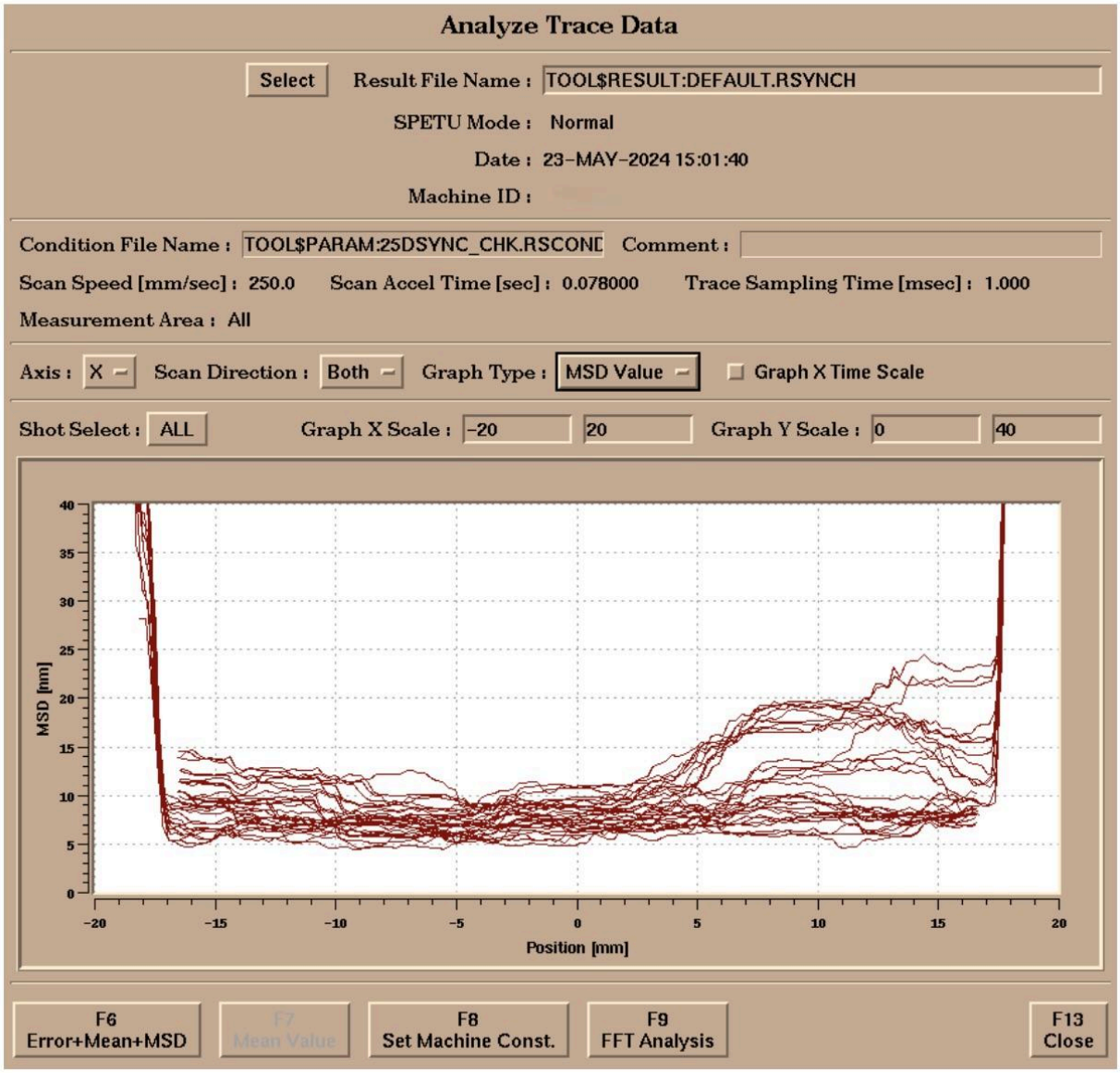
SPEC : 1) Mean ≤ 10nm (Within = -5nm ~+5nm)

2) MSD ≤ 25nm

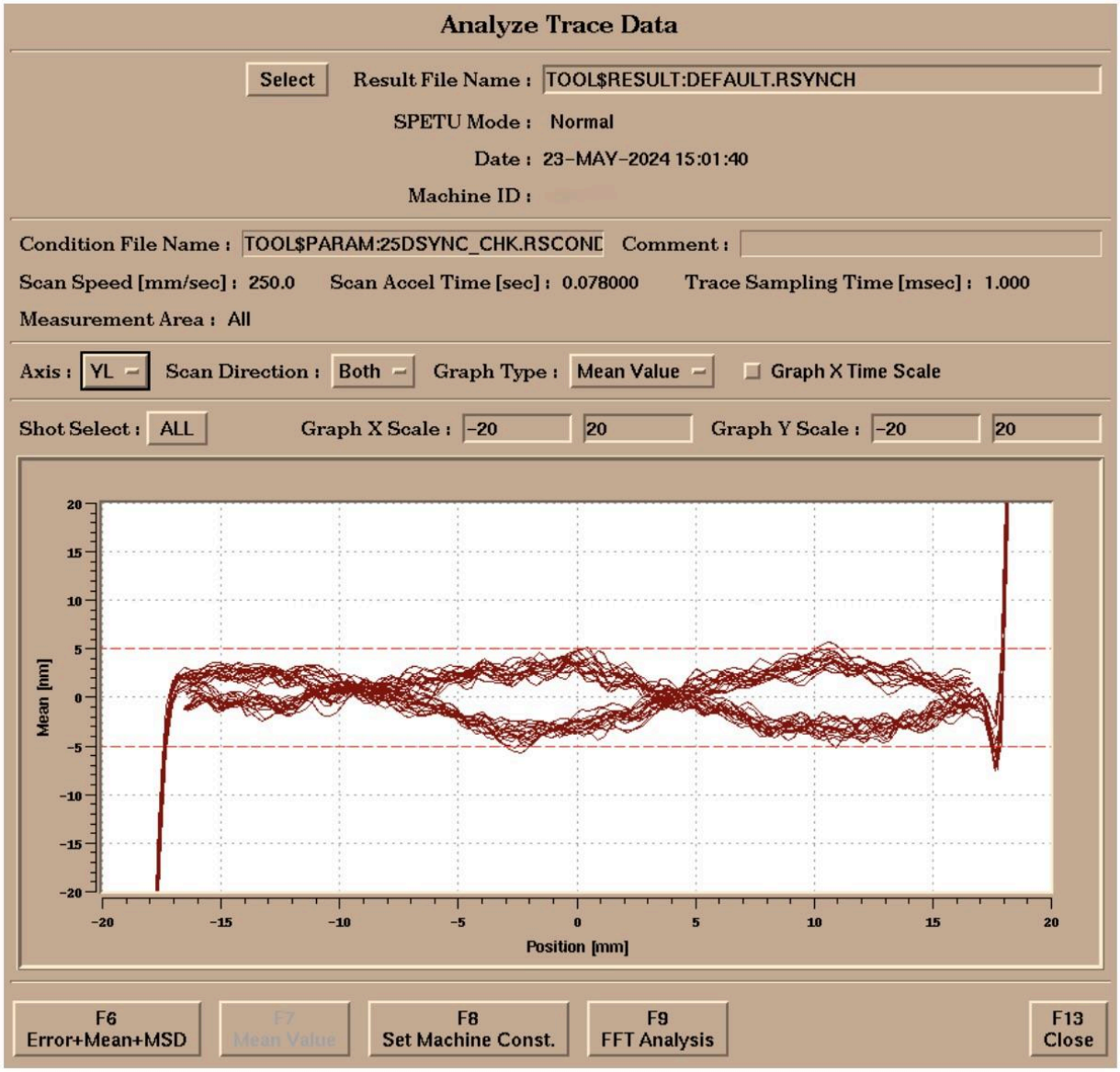
X MEAN Value : 10nm (-5nm ~ 5nm)



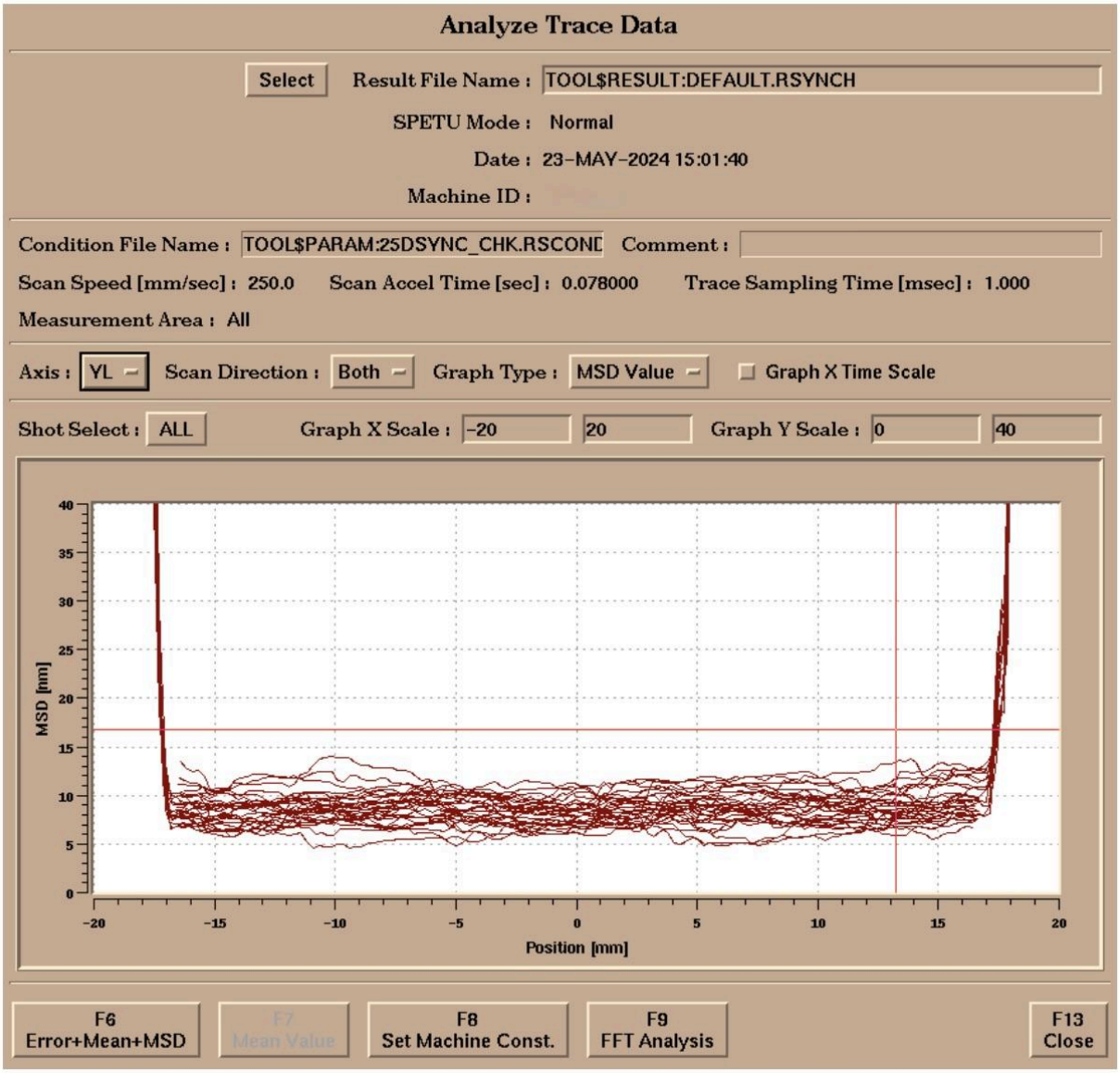
X MSD Max : 24nm



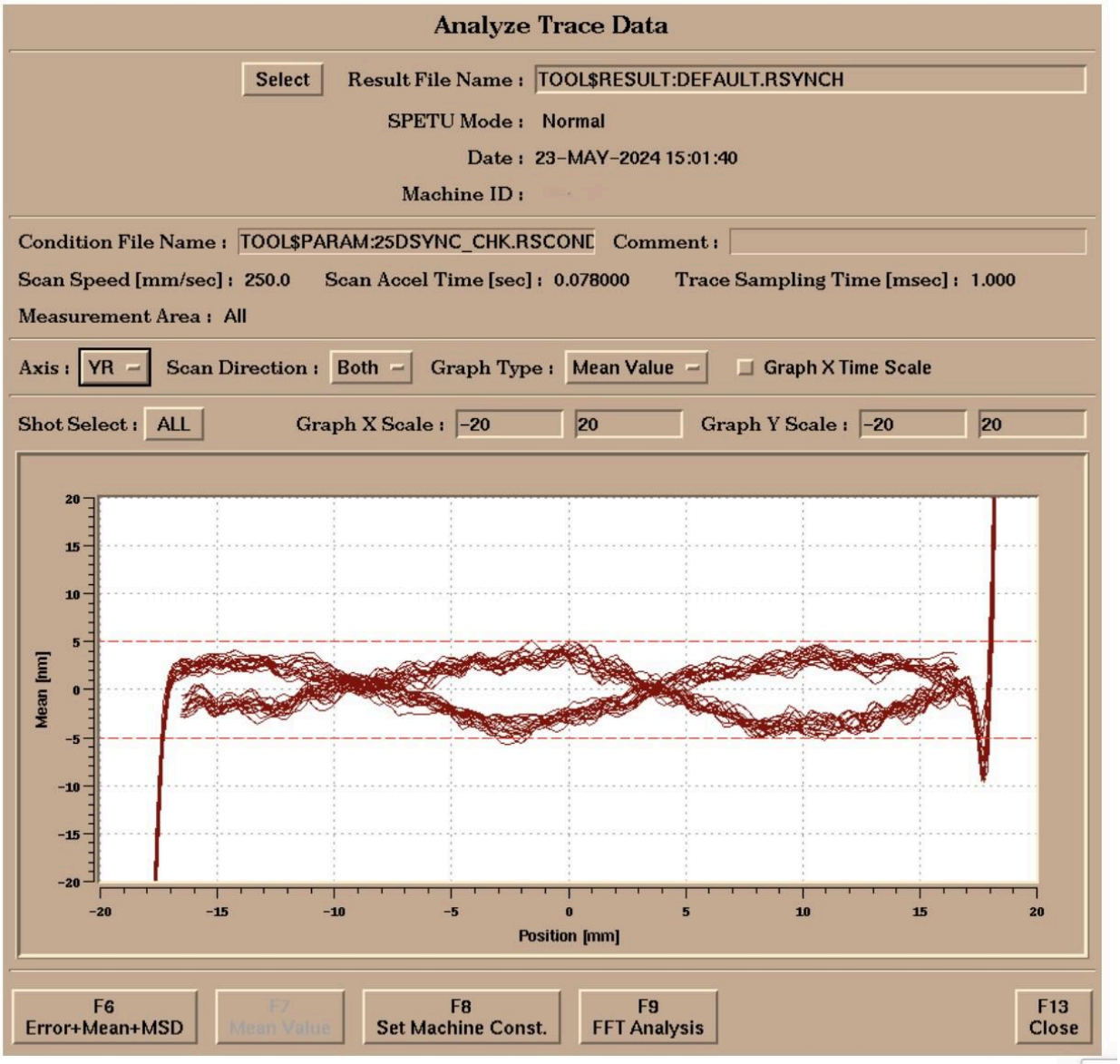
YL MEAN Value : 10nm (-5nm ~ 5nm)



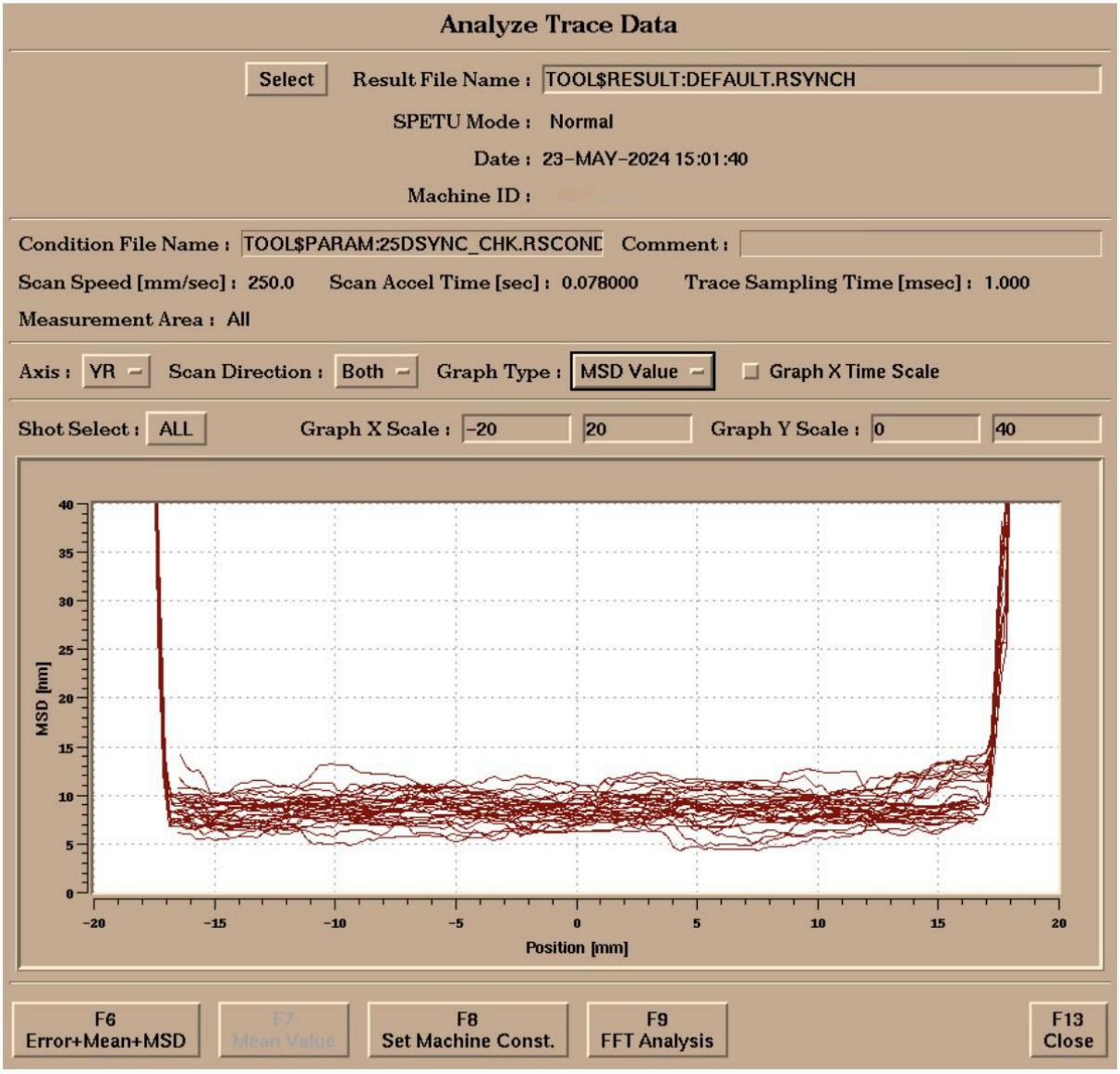
YL MSD Max : 14nm



YR Mean Value : 10nm (-5nm ~ 5nm)



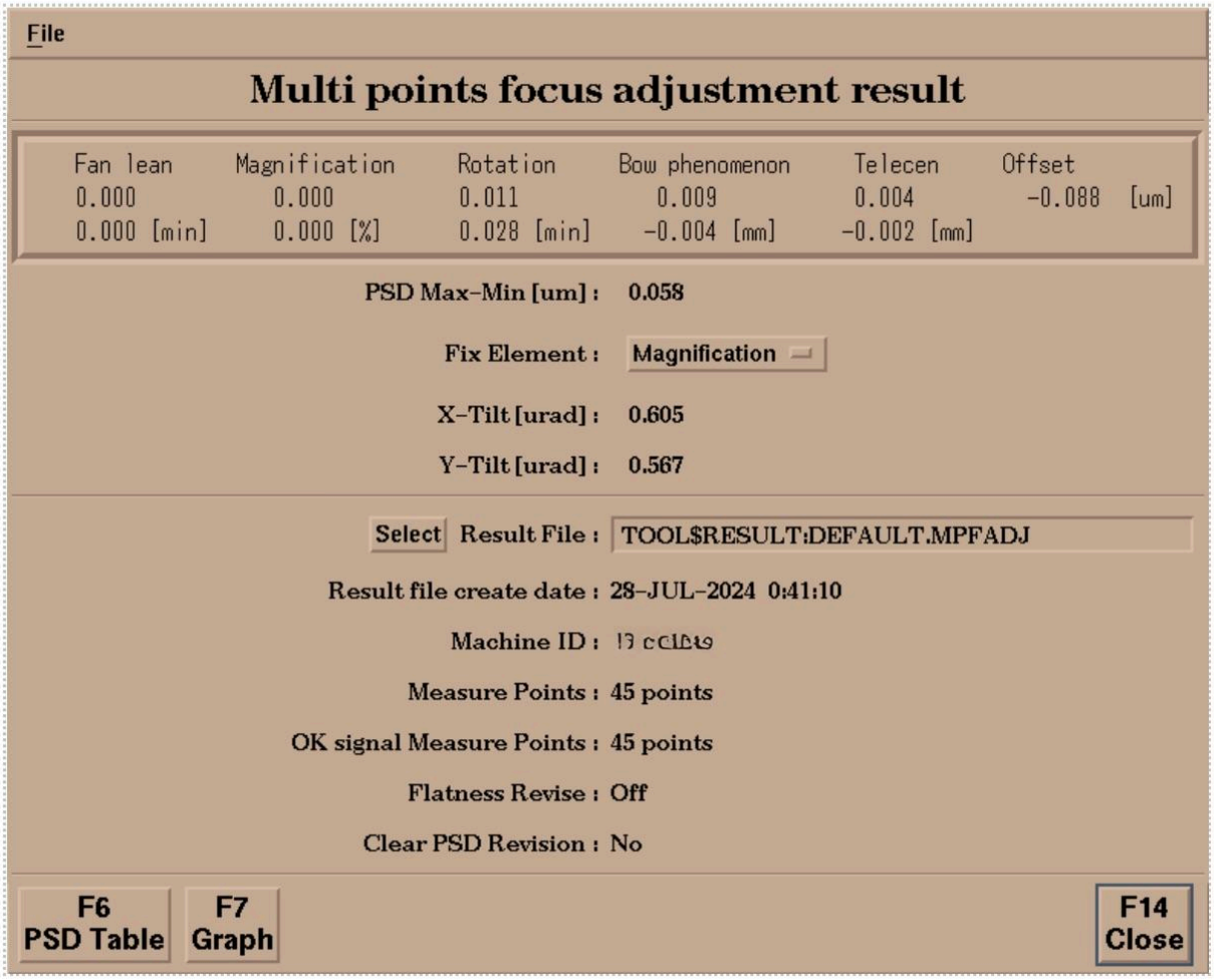
YR MSD Max : 14nm



15. AF Adjustment Result (2024):

SPEC: PSD Max – Min ≤ 0.2μm

Result: PSD Max – Min = 0.058μm

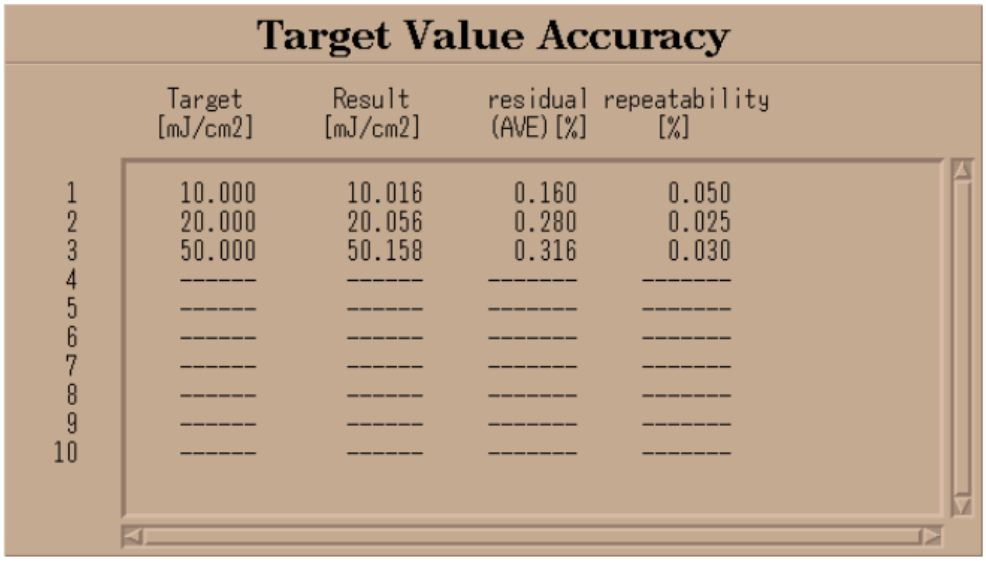


16. Integrator Accuracy (2024):

Conv NA/σ = 0.68/0.75

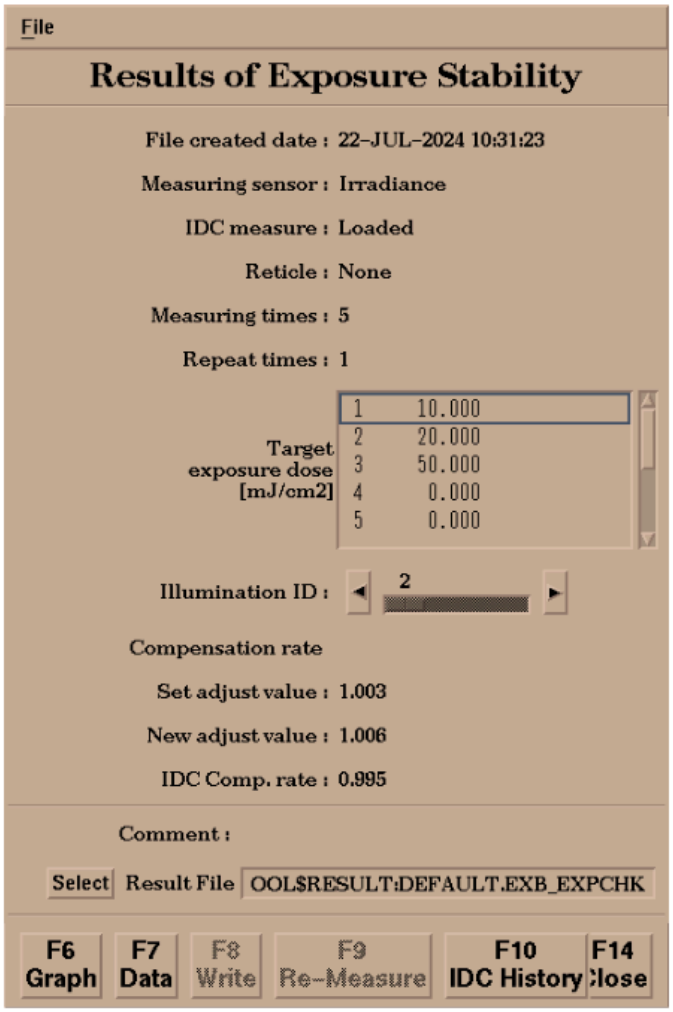
SPEC: Ave ≤ 1.3%

Result: Max = 0.32%



Target Value Accuracy

	Target [mJ/cm2]	Result [mJ/cm2]	residual (AVE) [%]	repeatability [%]
1	10.000	10.016	0.160	0.050
2	20.000	20.056	0.280	0.025
3	50.000	50.158	0.316	0.030
4	------	------	-------	-------
5	------	------	-------	-------
6	------	------	-------	-------
7	------	------	-------	-------
8	------	------	-------	-------
9	------	------	-------	-------
10	------	------	-------	-------



File

Results of Exposure Stability

File created date : 22-JUL-2024 10:31:23

Measuring sensor : Irradiance

IDC measure : Loaded

Reticle : None

Measuring times : 5

Repeat times : 1

Target exposure dose [mJ/cm2]

1	10.000
2	20.000
3	50.000
4	0.000
5	0.000

Illumination ID : 2

Compensation rate

Set adjust value : 1.003

New adjust value : 1.006

IDC Comp. rate : 0.995

Comment :

Select Result File OOL$RESULT:DEFAULT.EXB_EXPCHK

F6 Graph | F7 Data | F8 Write | F9 Re-Measure | F10 IDC History | F14 Close

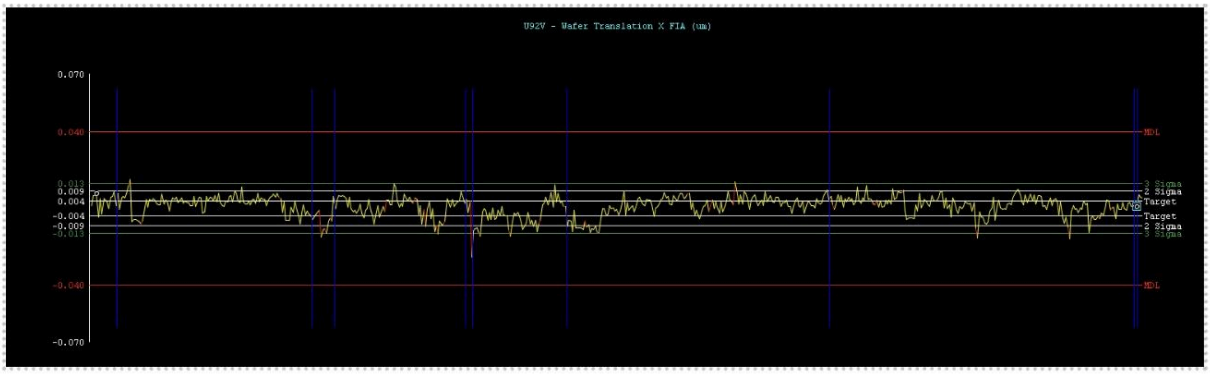
17-1 FIA (2024):

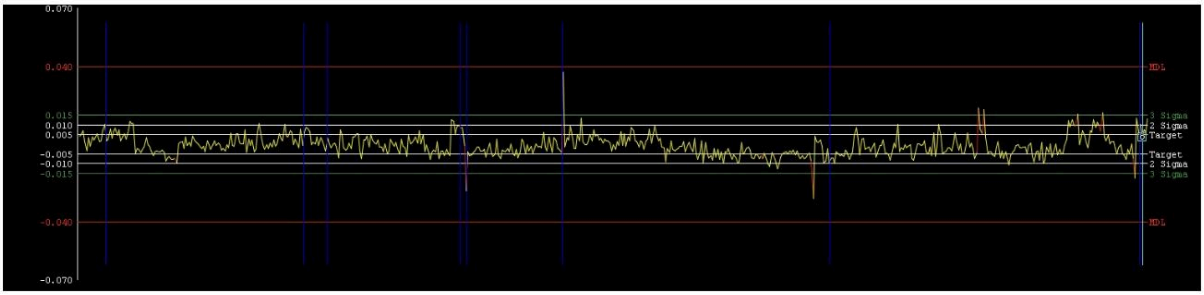
SPEC: FIA-EGA = |M| + 3σ ≤ 35nm

Result: FIA-EGA X = 20nm

FIA-EGA Y = 20nm

Data is from our Overlay FIA Check 2021-2024





17-2 LSA (2024):

SPEC: LSA-EGA = |M| + 3σ ≤ 40nm

Result: LSA-EGA X = 15nm

LSA-EGA Y = 15nm

Data is from ASML Overlay LSA Check 2021-2024